

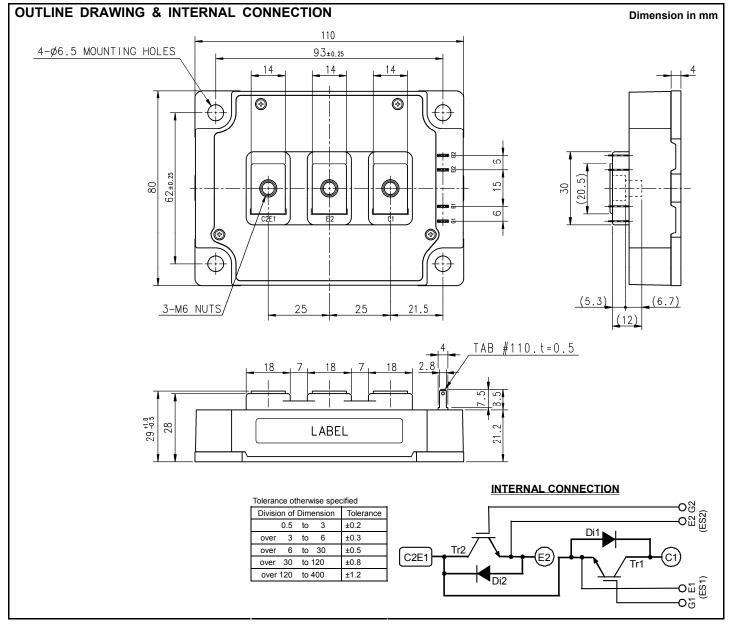
< IGBT MODULES > **CM450DY-24S**

HIGH POWER SWITCHING USE INSULATED TYPE

llector-emitter voltage V_{CES} 1 2 (aximum junction temperature T_{jmax}	
	7 5 °C
Flat base Type	
Copper base plate	
RoHS Directive compliance	
UL Recognized under UL1557, File E323585	
DC current rating is limited by power terminals.	
F	Copper base plate RoHS Directive compliance UL Recognized under UL1557, File E323585 DC current rating is limited by power terminals.

PLICATION

AC Motor Control, Motion/Servo Control, Power supply, etc.



ABSOLUTE MAXIMUM RATINGS (Tj=25 °C, unless otherwise specified)

Symbol	Item Conditions		Rating	Unit
V _{CES}	Collector-emitter voltage	G-E short-circuited	1200	V
V_{GES}	Gate-emitter voltage	C-E short-circuited	±20	V
lc	Collector ourrent	DC, T _C =125 °C (Note.2, 4)	410 *	^
I _{CRM}	Collector current	Pulse, Repetitive (Note.3)	900	
P _{tot}	Total power dissipation	T _C =25 °C (Note.2, 4)	3330	W
IE (Note.1)	Emitter current	T _C =25 °C (Note.2, 4)	410 *	^
(Note.1)		Pulse, Repetitive (Note.3)	900	A
Visol	Isolation voltage	Terminals to base plate, RMS, f=60 Hz, AC 1 min	2500	V
T _{jmax}	Maximum junction temperature	-	175	°C
T _{cmax}	Maximum case temperature	(Note.4)	125	
T _{jopr}	Operating junction temperature	-	-40 ~ +150	°C
T _{stg}	Storage temperature	-	-40 ~ +125	

ELECTRICAL CHARACTERISTICS (T_j=25 °C, unless otherwise specified)

Symbol	Item Conditions				Limits		Unit
Symbol	item	Conditions		Min.	Тур.	Max.	Unit
I _{CES}	Collector-emitter cut-off current	V _{CE} =V _{CES} , G-E short-circuited		-	-	1.0	mA
I _{GES}	Gate-emitter leakage current	V _{GE} =V _{GES} , C-E short-circuited		-	-	0.5	μA
$V_{\text{GE(th)}}$	Gate-emitter threshold voltage	I _C =45 mA, V _{CE} =10 V		5.4	6.0	6.6	V
V _{CEsat}		I _C =450 A ^(Note.5) ,	Tj=25 ℃	-	1.80	2.25	
		V _{GE} =15 V, Terminal,	T _j =125 °C	-	2.05	-	V
	Collector omitter acturation valtage	Refer to figure of test circuit	T _j =150 °C	-	2.10	-]
	Collector-emitter saturation voltage	I _C =450 A ^(Note.5) ,	Т _ј =25 °С	-	1.70	2.15	
		V _{GE} =15 V,	T _j =125 °C	-	1.90	-	V
		Chip	T _j =150 °C	-	1.95	-	1
Cies	Input capacitance					45	
C _{oes}	Output capacitance	V _{CE} =10 V, G-E short-circuited		-	-	9.0	nF
Cres	Reverse transfer capacitance		-	-	0.75	1	
Q _G	Gate charge	V _{cc} =600 V, I _c =450 A, V _{GE} =15 V	-	1050	-	nC	
t _{d(on)}	Turn-on delay time	N 000 X 1 450 A X 45	-	-	800		
tr	Rise time	V _{CC} =600 V, I _C =450 A, V _{GE} =±15	-	-	200		
t _{d(off)}	Turn-off delay time		-	-	600	ns	
t _f	Fall time	- R _G =0 Ω, Inductive load	-	-	300	1	
		I _E =450 A ^(Note.5) ,	T _i =25 °C	-	1.85	2.30	
		G-E short-circuited, Terminal,	T _i =125 °C	-	1.85	-	V
V _{EC} (Note.1)		Refer to figure of test circuit	T _i =150 °C	-	1.85	-	1
V _{EC}	Emitter-collector voltage	I _E =450 A ^(Note.5) ,	T _j =25 °C	-	1.70	2.15	
		G-E short-circuited,	T _j =125 °C	-	1.70	-	V
		Chip	T _i =150 °C	-	1.70	-	
t _{rr} (Note.1)	Reverse recovery time	V _{cc} =600 V, I _E =450 A, V _{GE} =±15	V,	-	-	300	ns
Qrr (Note.1)	Reverse recovery charge	$R_{g}=0 \Omega$, Inductive load		-	24	-	μC
Eon	Turn-on switching energy per pulse	V _{CC} =600 V, I _C =I _E =450 A,		-	54.9	-	
E _{off}	Turn-off switching energy per pulse	$V_{GE}=\pm 15 \text{ V}, \text{ R}_{G}=0 \Omega,$		-	48	-	mJ
Err (Note.1)	Reverse recovery energy per pulse	$T_i=150$ °C, Inductive load		-	32.4	-	mJ
R _{CC'+EE'}	Internal lead resistance	Main terminals -chip, per switch	n, T _C =25 °C	-	-	0.7	mΩ
r _g	Internal gate resistance	Per switch		-	4.3	-	Ω

THERMAL RESISTANCE CHARACTERISTICS

Symbol	Item	Conditions	Limits			Unit
			Min.	Тур.	Max.	Unit
R _{th(j-c)Q}	Thermal resistance (Note.4)	Junction to case, per IGBT	-	-	45	K/kW
R _{th(j-c)D}		Junction to case, per FWDi	-	-	68	K/kW
R _{th(c-s)}	Contact thermal resistance (Note.4)	Case to heat sink, per 1/2 module, Thermal grease applied ^(Note.6)	-	18	-	K/kW

MECHANICAL CHARACTERISTICS

Symbol	Item	Conditions		Limits			Unit
				Min.	Тур.	Max.	Unit
Mt	Mounting torque	Main terminals	M 6 screw	3.5	4.0	4.5	N∙m
Ms		Mounting to heat sink	M 6 screw	3.5	4.0	4.5	N∙m
m	Weight	-		-	580	-	g
ec	Flatness of base plate	On the centerline X, Y (Note.7)		-100	-	+100	μm

Note1. Represent ratings and characteristics of the anti-parallel, emitter-collector free wheeling diode (FWDi).

2. Junction temperature (T_j) should not increase beyond T_{jmax} rating.

3. Pulse width and repetition rate should be such that the device junction temperature (T_j) dose not exceed T_{jmax} rating.

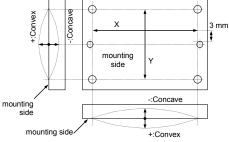
4. Case temperature (T_c) and heat sink temperature (T_s) are defined on the each surface (mounting side) of base plate and heat sink just under the chips. Refer to figure of chip location.

The heat sink thermal resistance should measure just under the chips.

5. Pulse width and repetition rate should be such as to cause negligible temperature rise.

6. Typical value is measured by using thermally conductive grease of λ =0.9 W/(m·K).

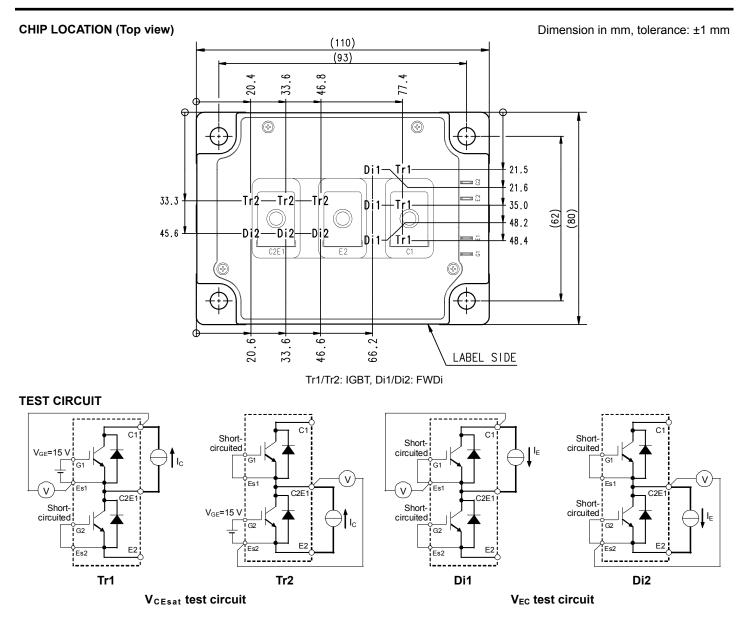
7. Base plate (mounting side) flatness measurement points (X, Y) are as follows of the following figure.

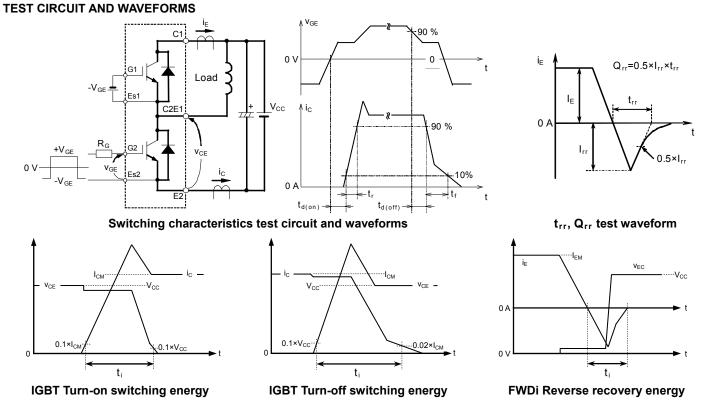


*. DC current rating is limited by power terminals.

RECOMMENDED OPERATING CONDITIONS

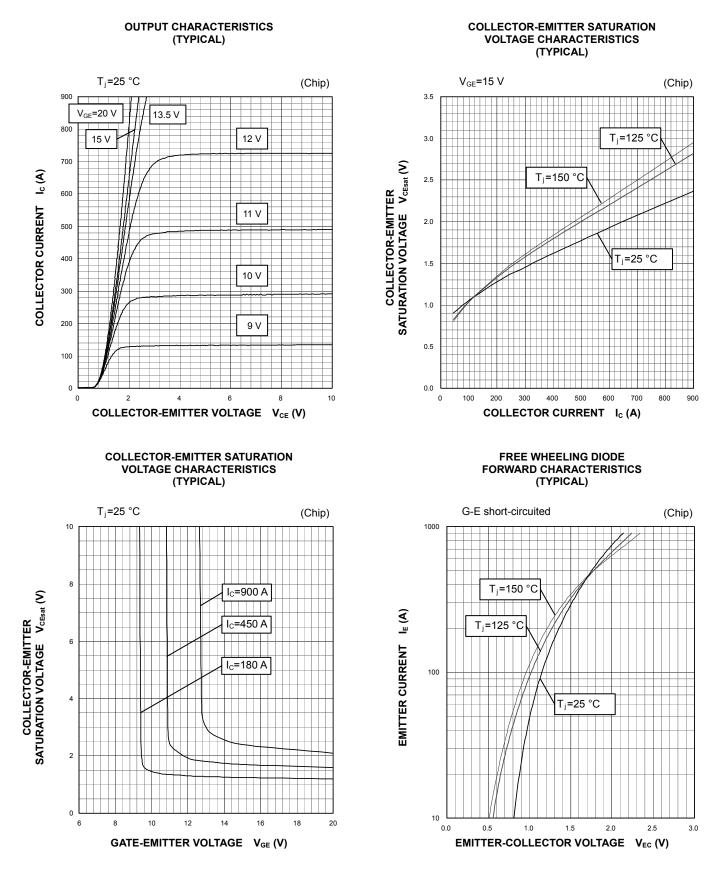
Symbol	Item	Conditions	Limits			Unit
			Min.	Тур.	Max.	Unit
Vcc	(DC) Supply voltage	Applied across C1-E2	-	600	850	V
V _{GEon}	Gate (-emitter drive) voltage	Applied across G1-Es1/G2-Es2	13.5	15.0	16.5	V
R _G	External gate resistance	Per switch	0	-	8	Ω



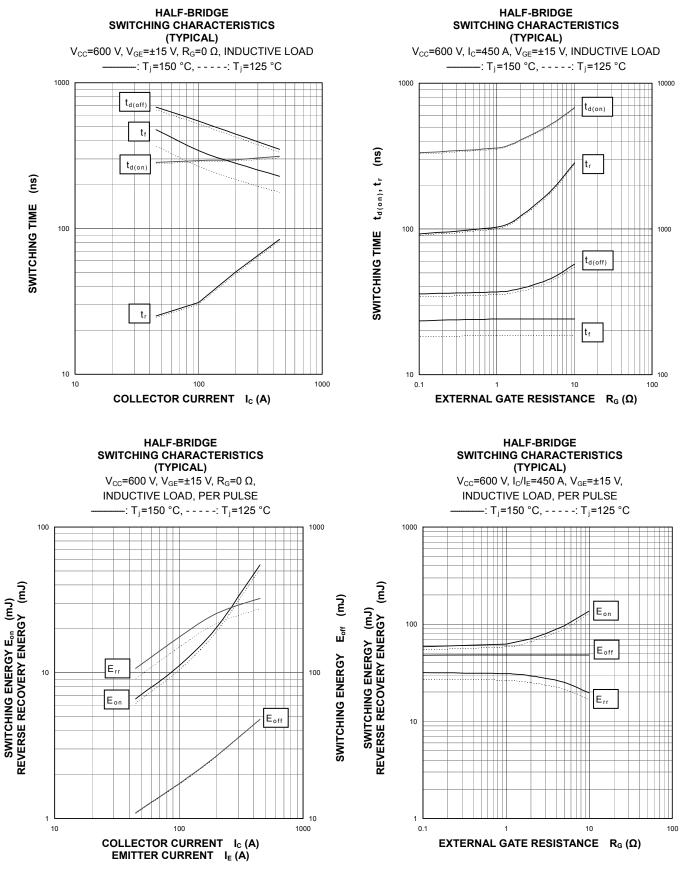


Turn-on / Turn-off switching energy and Reverse recovery energy test waveforms (Integral time instruction drawing)

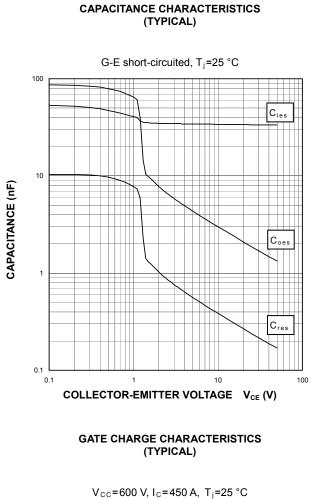
PERFORMANCE CURVES

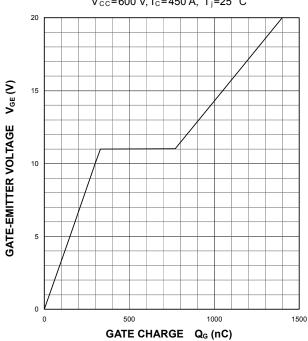


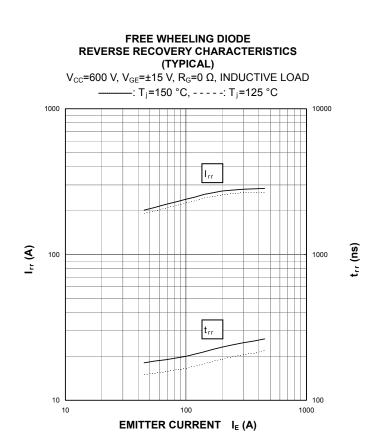
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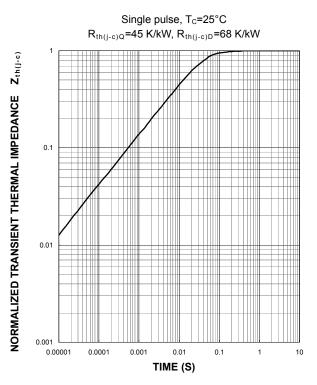
PERFORMANCE CURVES







TRANSIENT THERMAL IMPEDANCE CHARACTERISTICS (MAXIMUM)



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